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Session A: Wireless Communication Test and Measurements

Working with the Latest Wireless Devices and Standards (Invited)''''P IC

Fred Schindler, RFMD

Folded Planar Marchand Balun With Improved Isolation for Radio Frequency Automated Test''''3 Equipment Applications

Claudio Montiel, Texas A&M University - Kingsville, Kingsville, United States

Sensitivity Analysis of Wafer-Level Over-Temperature RF Calibration ''''6

Andrej Rumiantsev, Gavin Fisher, Ralf Doerner, Cascade Microtech, Inc, Beaverton, United States

A Neural Network Approach to Smooth Calibrated Data Corrupted From Switching Errors ''''9

Andres Zarate-de Landa¹, Manuel Pulido-Gaytan¹, J Reynoso-Hernandez¹, Patrick Roblin², Jose Loo-Yau³
¹CICESE, Ensenada, Mexico, ²The Ohio State University, Columbus, United States, ³Cinvestav, Zapopan, Mexico

Session B: MM-Wave Measurements

Millimeter-Wave Modulated Signal Measurements (Invited)''''P IC

Kate Remley, NIST

Characterizing WR-8 Waveguide-to-CPW Probes Using Two Methods Implemented within the''''33 NIST Uncertainty Framework

Jeffrey Jargon¹, Uwe Arz², Dylan Williams¹
¹NIST, Boulder, United States, ²PTB, Braunschweig, Germany

Characterizing Artefact Standards for Use with Coaxial Vector Network Analyzers at Millimeter-''''38 wave Frequencies

Dexter Shelton¹, Martin Salter², Nick Ridler², Masahiro Horibe³
¹US Army Primary Standards Laboratory, Redstone Arsenal, United States, ²National Physical Laboratory, Teddington, United Kingdom,
³National Metrology Institute of Japan, Tsukuba, Japan

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Yuenie Lau, David Vondran, OML, Inc., Morgan Hill, United States

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Basim Noori, Freescale

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Shengjie Gao, Chan-Wang Park, University of Quebec in Rimouski, Rimouski, CanadaStates

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Luca Galatro¹, Mauro Marchetti², Marco Spirito³
¹Delft University of Technology, Delft, Netherlands, ²Anteverta-mw B.V., Delft, Netherlands, ³Delft University of Technology, Delft, Netherlands

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Claude Setzer, Wireless Technology Center, Indiana Univ.-Purdue

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Yeou-Song (Brian) Lee, Anritsu Company, Morgan Hill, United States

Pulsed RF Calibration for NVNA Measurements""6;

Patrick Roblin¹, Youngseo Ko¹, Haedong Jang¹, Jean-Pierre Teyssier²
¹OSU, Columbus, United States, ²Agilent, Santa Rosa, CA United States

Comparison of Power Ratio and Vector Network Analyzer Techniques for Measuring Attenuation""77

Caitlin Chirgwin¹, Thomas Crowley², Weihai Fang³, Denis LeGolvan²
¹St. Joseph's University, Philadelphia, United States, ²National Institute of Standards and Technology, Boulder, United States, ³Beijing Institute of Radio Metrology and Measurement, Beijing, China

Session E: Noise Measurements

Evolution of Noise Parameters & Load-Pull Measurement Systems with Impedance Tuner ""P IC Technologies (Invited)

Gary Simpson, Maury Microwave

Method for Obtaining Noise Parameters Using a Vector Network Analyzer with an Integrated ""83 Noise Receiver

Roger Hayward, TriQuint Semiconductor, Inc., Hillsboro, United States

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Jon Martens, Anritsu, Morgan Hill, United States

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Ken Wong, Agilent Technologies, Inc., Santa Rosa, United States

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Karel Hoffmann, Martin Randus, Czech Technical University in Prague , Prague 6, Czech Republic

Computation of rain scattering properties at SHF and EHF for radio wave propagation in South ""P IC Africa

Pius Owolawi, Senzo Malinga, Mangosuthu University Of Technology, Durban, South Africa

The improved "floating loading" method for measuring immittance parameters of two-ports ""P IC

Ludmila Lischinskaya, Nickloay Filinyuk, Alexander Lazarev, VinnitsaNational Technical Univ., Vinnitsa, Ukraine

Comparison of Equivalent Source Match Measurements of a 40 GHz Power Splitter using Scalar ""9: and Vector Network Analyzer

Yeou-Song (Brian) Lee, Anritsu Company, Morgan Hill, United States